## Application/Control No. Applicant(s)/Patent Under Reexamination 09/992,624 HIEW ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 Fred Ferris 2128 **U.S. PATENT DOCUMENTS Document Number** Date Classification Name Country Code-Number-Kind Code MM-YYYY Α US-В US-С US-D US-US-Ε F US-US-G Н US-US-1 US-J US-Κ US-Ł US-М **FOREIGN PATENT DOCUMENTS** Document Number Date Country Name Classification Country Code-Number-Kind Code MM-YYYY Ν 0 Р Q R S Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U "An Analysis of Geometric Modeling in Database Systems", Kemper et al, ACM Computing Surveys, Vol. 19, No. 1, March 1987

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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